

MINTEM SCHOOL 10 -15th October 2011
Room Beaumaretz, ENSCL, University of Lille 1

	<i>Monday</i>	<i>Tuesday</i>	<i>Wednesday</i>	<i>Thursday</i>	<i>Friday</i>
9.00	Welcome	Imaging (BF/DF/defects) Diffraction N. Miyajima, CM30 A. Mussi, Tecnai	Diffraction SAED Kikuchi (LA)CBED N. Miyajima, CM30 D. Jacob, Tecnai	HRTEM G1/G2 K. Pollok, CM30 EELS G1/G2 N. Miyajima, A. Mussi Tecnai	EDX/STEM H. Leroux, Tecnai
10.00	Sample Prep and microscope presentation A. Mussi				EDX/STEM H. Leroux
11.00					
12.00	lunch				
13.30	lunch				
15.00	TEM Ray Path D. Jacob	Image/Amplitude (perfect crystal) K. Pollok	Crystallography Spot patt. Indexing D. Jacob	Phase contrast K. Pollok	Evaluation/ Examination
15.30	lunch				
17.00	e-/solid EDX/EELS H. Leroux	Defects N. Miyajima, A. Mussi	Disk patterns D. Jacob	EELS N. Miyajima	

TEM session (TS)
lecture/practical (LP)